

## CY7C1011DV33

# 2-Mbit (128 K × 16) Static RAM

#### Features

- Pin-and function-compatible with CY7C1011CV33
- High speed □ t<sub>AA</sub> = 10 ns
- Low active power □ I<sub>CC</sub> = 90 mA @ 10 ns (Industrial)
- Low CMOS standby power □ I<sub>SB2</sub> = 10 mA
- Data Retention at 2.0 V
- Automatic power-down when deselected
- Independent control of upper and lower bits
- Easy memory expansion with CE and OE features
- Available in Pb-free 44-pin TSOP II, and 48-ball VFBGA

#### **Functional Description**

The CY7C1011DV33<sup>[1]</sup> is a high-performance CMOS Static RAM organized as 128 K words by 16 bits.

Writing to the device is accomplished by taking Chip Enable  $\overline{(CE)}$ and Write Enable (WE) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>), is written into the location specified on the address pins (A<sub>0</sub> through A<sub>16</sub>). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O<sub>8</sub> through I/O<sub>15</sub>) is written into the location specified on the address pins (A<sub>0</sub> through A<sub>16</sub>).

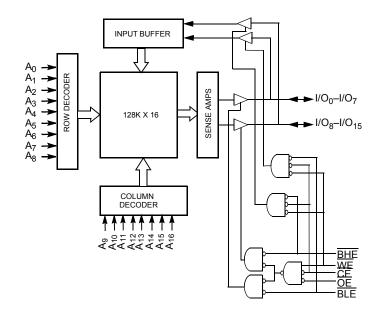
<u>Reading</u> from the device is <u>accomplished</u> by taking Chip Enable (CE) an<u>d</u> Output Enable (OE) LOW <u>while</u> forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the<u>address</u> pins will appear on I/O<sub>0</sub> to I/O<sub>7</sub>. If Byte High Enable (BHE) is LOW, then data from memory will appear on I/O<sub>8</sub> to I/O<sub>15</sub>. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins  $(I/O_0 \text{ through } I/O_{15})$  are placed in a high-impedance state when the device is deselected ( $\overline{CE} \text{ HIGH}$ ), the outputs are disabled ( $\overline{OE} \text{ HIGH}$ ), the BHE and BLE are disabled (BHE, BLE HIGH), or during a write operation ( $\overline{CE} \text{ LOW}$ , and WE LOW).

The CY7C1011DV33 is available in standard Pb-free 44-pin TSOP II with center power and ground pinout, as well as 48-ball very fine-pitch ball grid array (VFBGA) packages.

For a complete list of related resources, click here.

#### Logic Block Diagram



#### Note

1. For guidelines on SRAM system design, please refer to the "System Design Guidelines" Cypress application note, available on the internet at www.cypress.com

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# CY7C1011DV33

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## **Selection Guide**

Description	-10	Unit
Maximum Access Time	10	ns
Maximum Operating Current	90	mA
Maximum CMOS Standby Current	10	mA

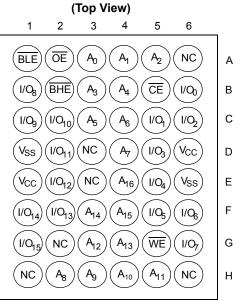
## **Pin Configurations**

#### Figure 1. 44-pin TSOP II pinout (Top View)

	TSOF	) II		
	Top Vi	ew		
	<b>Top Vi</b> 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16	44 43 42 41 40 39 38 37 36 35 34 33 32 31 30 29	זכונוסט המכור הכור הכור הכור הכור הכור הכור הכור ה	A5 A6 A0 BBU V014 V02 SC V010 V02 V010 V02 V010 V02 V0010 V02 V0010 V02 V0010 V02 V000 V000
I <u>/O7</u> WE C A <sub>16</sub> C	-			I/O <sub>8</sub> NC A <sub>8</sub>
A <sub>15</sub> A <sub>14</sub> A <sub>13</sub> A <sub>12</sub> A <sub>12</sub>	19 20 21 22	26 25 24 23		A <sub>9</sub> A <sub>10</sub> A <sub>11</sub> NC

## Figure 2. 48-ball VFBGA pinout (Top View)

48-ball VFBGA





### **Maximum Ratings**

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature65 °C to +150 °C
Ambient temperature with power applied–55 °C to +125 °C
Supply voltage on $V_{CC}$ to relative GND $^{[2]}$ –0.3 V to +4.6 V
DC voltage applied to outputs in high Z State $^{[2]}$ 0.3 V to V_{CC} + 0.3 V

DC input voltage [2]	. –0.3 V to V <sub>CC</sub> + 0.3 V
Current into outputs (LOW)	
Static discharge voltage (per MIL-STD-883, method 3015)	> 2001 V
Latch-up current	> 200 mA

## **Operating Range**

Range	Ambient Temperature	V <sub>cc</sub>
Industrial	–40 °C to +85 °C	$3.3~V\pm0.3~V$

### **DC Electrical Characteristics**

Over the Operating Range

Deremeter	Description Test Condi			-	10	Unit
Parameter	Description	Test Conditions		Min	Max	Unit
V <sub>OH</sub>	Output HIGH voltage	V <sub>CC</sub> = Min, I <sub>OH</sub> = -4.0 mA		2.4	-	V
V <sub>OL</sub>	Output LOW voltage	V <sub>CC</sub> = Min, I <sub>OL</sub> = 8.0 mA		-	0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage <sup>[3]</sup>			-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_I \le V_{CC}$		-1	+1	μA
I <sub>OZ</sub>	Output leakage current	$GND \leq V_{OUT} \leq V_{CC}$ , Output Disabled		-1	+1	μA
I <sub>CC</sub>	V <sub>CC</sub> operating supply current	$V_{CC}$ = Max, f = f <sub>MAX</sub> = 1/t <sub>RC</sub>	100 MHz	-	90	mA
			83 MHz	_	80	
			66 MHz	-	70	
			40 MHz	-	60	
I <sub>SB1</sub>	Automatic CE Power-down Current — TTL Inputs	$\begin{array}{l} \text{Max V}_{\text{CC}}, \ \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or } \text{V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \ \text{f} = \text{f}_{\text{MAX}} \end{array}$		-	20	mA
I <sub>SB2</sub>	Automatic CE Power-down Current — CMOS Inputs	$\begin{array}{l} \text{Max V}_{\text{CC}}, \ \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or } \text{V}_{\text{IN}} \leq 0.3 \text{ V}, \text{ f} = 0 \end{array}$		_	10	mA

Notes

2. Tested initially and after any design or process changes that may affect these parameters. 3. V<sub>IL</sub> (min) = -2.0 V and V<sub>IH</sub>(max) = V<sub>CC</sub> + 2 V for pulse durations of less than 20 ns.



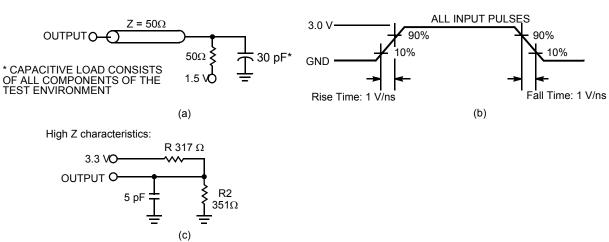
## Capacitance

Parameter <sup>[4]</sup>	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input capacitance	T <sub>A</sub> = 25 °C, f = 1 MHz, V <sub>CC</sub> = 3.3 V	8	pF
C <sub>OUT</sub>	I/O capacitance		8	pF

#### **Thermal Resistance**

Parameter <sup>[4]</sup>	Description	Test Conditions	TSOP II	VFBGA	Unit
$\Theta_{JA}$		Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	50.66	27.89	°C/W
Θ <sup>JC</sup>	Thermal resistance (junction to case)		17.17	14.74	°C/W

### **AC Test Loads and Waveforms**



#### Figure 3. AC Test Loads and Waveforms <sup>[5]</sup>

#### Note

- 4. Tested initially and after any design or process changes that may affect these parameters.
- 5. AC characteristics (except high Z) are tested using the load conditions shown in (a). High Z characteristics are tested for all speeds using the test load shown in (c).

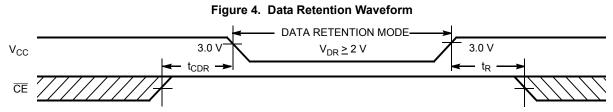


## **Data Retention Characteristics**

Over the Operating Range

Parameter	Description	Conditions <sup>[6]</sup>	Min	Max	Unit
V <sub>DR</sub>	V <sub>CC</sub> for data retention		2.0	-	V
I <sub>CCDR</sub>	Data retention current		-	10	mA
t <sub>CDR</sub> <sup>[7]</sup>	Chip deselect to data retention time	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	0	-	ns
t <sub>R</sub> <sup>[8]</sup>	Operation recovery time		t <sub>RC</sub>	_	ns

#### **Data Retention Waveform**



Notes

- 6. No input may exceed V<sub>CC</sub> + 0.3 V. 7. Tested initially and after any design or process changes that may affect these parameters. 8. Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min.)</sub>  $\geq$  50 µs or stable at V<sub>CC(min.)</sub>  $\geq$  50 µs.



## **AC Switching Characteristics**

Over the Operating Range

Parameter <sup>[9]</sup>	Description	-	-10	
Parameter	Description		Max	Unit
Read Cycle				
t <sub>power</sub> <sup>[10]</sup>	V <sub>CC</sub> (typical) to the first access	100	-	μS
t <sub>RC</sub>	Read cycle time	10	-	ns
t <sub>AA</sub>	Address to data valid	_	10	ns
t <sub>OHA</sub>	Data hold from address change	3	-	ns
t <sub>ACE</sub>	CE LOW to data valid	_	10	ns
t <sub>DOE</sub>	OE LOW to data valid	_	5	ns
t <sub>LZOE</sub>	OE LOW to low Z [11]	0	-	ns
t <sub>HZOE</sub>	OE HIGH to high Z <sup>[11, 12]</sup>	_	5	ns
t <sub>LZCE</sub>	CE LOW to low Z [11]	3	-	ns
t <sub>HZCE</sub>	CE HIGH to high Z <sup>[11, 12]</sup>	_	5	ns
t <sub>PU</sub>	CE LOW to power-up	0	-	ns
t <sub>PD</sub>	CE HIGH to power-down	_	10	ns
t <sub>DBE</sub>	Byte enable to data valid	-	5	ns
t <sub>LZBE</sub>	Byte enable to low Z	0	-	ns
t <sub>HZBE</sub>	Byte disable to high Z	_	6	ns
Write Cycle [1	3, 14]			
t <sub>WC</sub>	Write cycle time	10	-	ns
t <sub>SCE</sub>	CE LOW to write end	7	-	ns
t <sub>AW</sub>	Address set-up to write end	7	-	ns
t <sub>HA</sub>	Address hold from write end	0	_	ns
t <sub>SA</sub>	Address set-up to write start	0	_	ns
t <sub>PWE</sub>	WE pulse width	7	_	ns
t <sub>SD</sub>	Data set-up to write end	5	_	ns
t <sub>HD</sub>	Data hold from write end	0	-	ns
t <sub>LZWE</sub>	WE HIGH to low Z [11]	3	-	ns
t <sub>HZWE</sub>	WE LOW to high Z <sup>[11, 12]</sup>	_	5	ns
t <sub>BW</sub>	Byte enable to end of write	7	-	ns

Notes

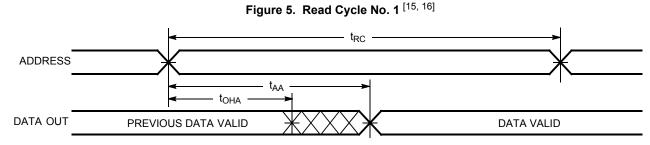
9. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
10. t<sub>POWER</sub> gives the minimum amount of time that the power supply should be at typical V<sub>CC</sub> values until the first memory access is performed.
11. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZDE</sub> is less than t<sub>LZDE</sub>, t<sub>HZBE</sub> is less than t<sub>LZBE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.

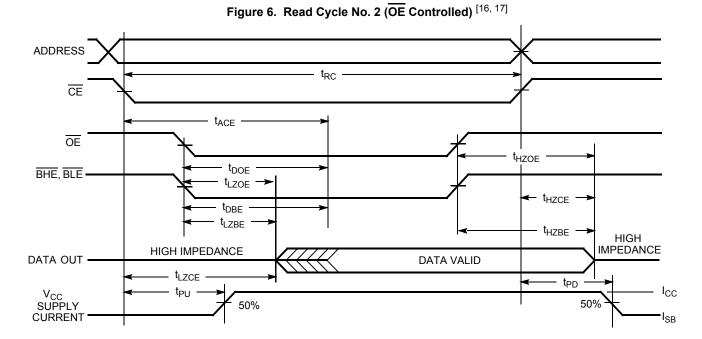
12. t<sub>HZOE</sub>, t<sub>HZDE</sub>, t<sub>HZDE</sub> and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (d) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.

13. The internal write time of the memory is defined by the overlap of  $\overline{CE}$  LOW, and  $\overline{WE}$  LOW.  $\overline{CE}$  and  $\overline{WE}$  must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write. 14. The minimum write cycle pulse width for Write Cycle No. 4 (WE Controlled,  $\overline{OE}$  LOW) should be the sum of t<sub>SD</sub> and t<sub>HZWE</sub>.



**Switching Waveforms** 



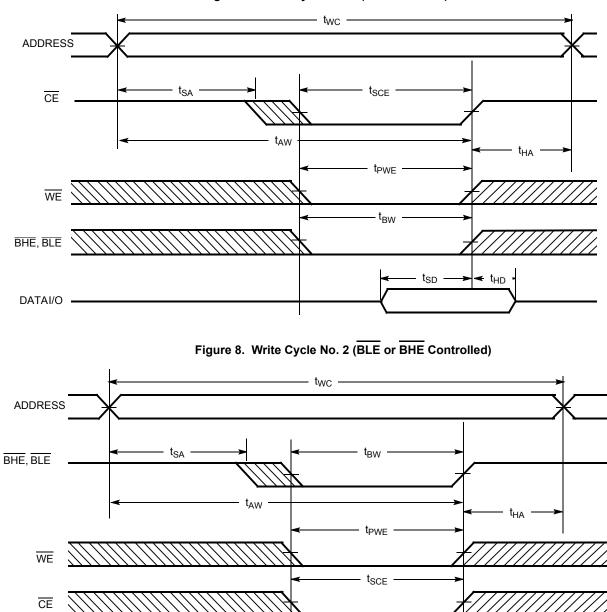


#### Notes

- 15. <u>Dev</u>ice is continuously selected. <u>OE</u>, <u>CE</u>, <u>BHE</u> and/or <u>BHE</u> = V<sub>IL</sub>. 16. WE is HIGH for read cycle.
- 17. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.



### Switching Waveforms (continued)



t<sub>SD</sub>

< t<sub>HD</sub> →

Figure 7. Write Cycle No. 1 (CE Controlled) <sup>[18, 19]</sup>

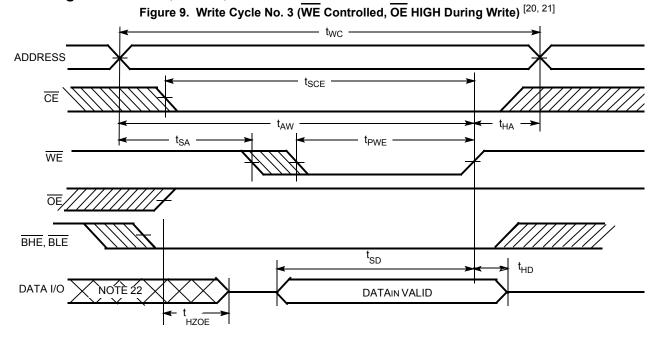
#### Notes

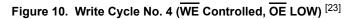
DATA I/O

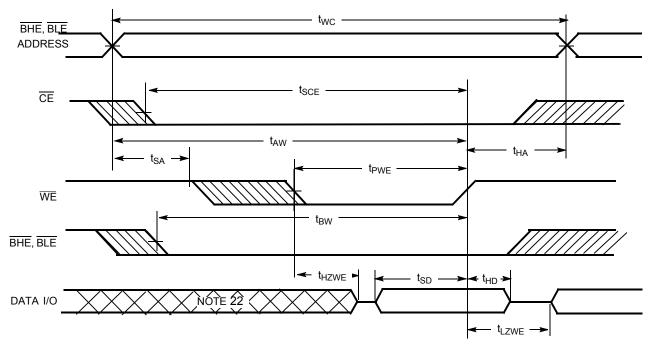
18. Data I/O is high-impedance if OE or BHE and/or BLE = V<sub>IH</sub>.
 19. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.



#### Switching Waveforms (continued)







#### Notes

- 20. Data I/O is high-impedance if OE or BHE and/or BLE = V<sub>IH</sub>. 21. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state. 22. During this period the I/Os are in the output state and <u>input</u> signals should not be applied. 23. The minimum write pulse width for Write Cycle No. 4 (WE controlled, OE LOW) should be the sum of t<sub>SD</sub> and t<sub>HZWE</sub>.



## Truth Table

CE	OE	WE	BLE	BHE	I/O <sub>0</sub> –I/O <sub>7</sub>	I/O <sub>8</sub> –I/O <sub>15</sub>	Mode	Power
Н	Х	Х	Х	Х	High Z	High Z	Power-down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read all bits	Active (I <sub>CC</sub> )
L	L	Н	L	Н	Data Out	High Z	Read lower bits only	Active (I <sub>CC</sub> )
L	L	Н	Н	L	High Z	Data Out	Read upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write all bits	Active (I <sub>CC</sub> )
L	Х	L	L	Н	Data In	High Z	Write lower bits only	Active (I <sub>CC</sub> )
L	Х	L	Н	L	High Z	Data In	Write upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Х	High Z	High Z	Selected, outputs disabled	Active (I <sub>CC</sub> )

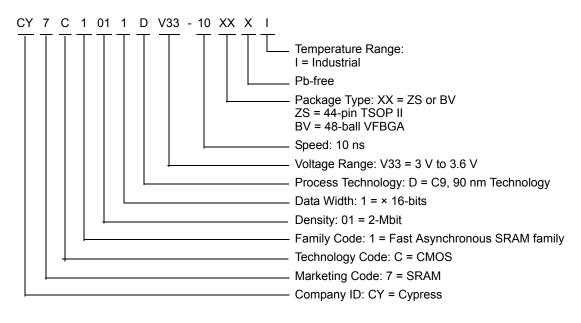


#### **Ordering Information**

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1011DV33-10ZSXI	51-85087	44-pin TSOP II (Pb-free)	Industrial
	CY7C1011DV33-10BVXI	51-85150	48-ball VFBGA (Pb-free)	

Please contact your local Cypress sales representative for availability of these parts

#### **Ordering Code Definitions**





#### **Package Diagrams**

Figure 11. 44-pin TSOP Z44-II Package Outline, 51-85087

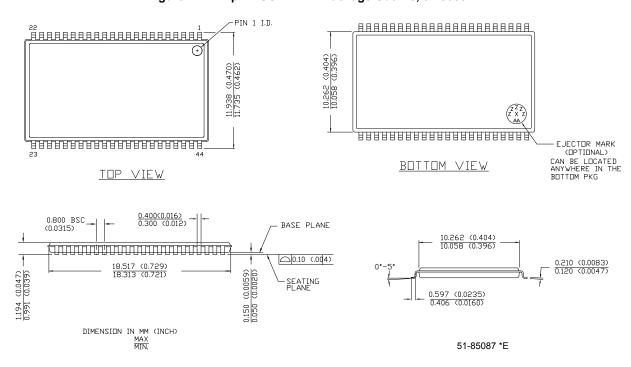
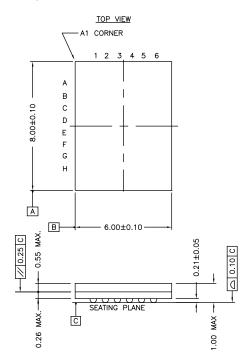
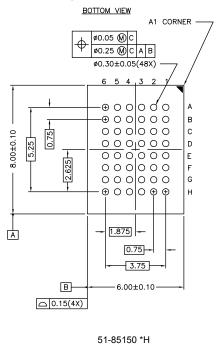


Figure 12. 48-ball VFBGA (6 × 8 × 1 mm) BV48/BZ48 Package Outline, 51-85150







## Acronyms

Acronym	Description				
CMOS	Complementary Metal Oxide Semiconductor				
CE	Chip Enable				
I/O	Input/Output				
OE	Output Enable				
SRAM	Static Random Access Memory				
TSOP	Thin Small Outline Package				
TTL	Transistor-Transistor Logic				
VFBGA	Very Fine-Pitch Ball Grid Array				
WE	Write Enable				

### **Document Conventions**

#### **Units of Measure**

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μs	microsecond
μA	microampere
mA	milliampere
ns	nanosecond
%	percent
pF	picofarad
V	volt
W	watt





# **Document History**

Document Title: CY7C1011DV33, 2-Mbit (128 K ×	16) Static RAM
Document Number: 38-05609	•

Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change
**	250650	See ECN	RKF	New data sheet.
*A	399070	See ECN	NXR	Changed from Advance to Preliminary Changed address of Cypress Semiconductor Corporation on Page# 1 from "3901 North First Street" to "198 Champion Court" Removed TQFP Package from product offering Removed –15 speed bin Corrected DC voltage limits in maximum ratings section from –0.5 to –0.3V and $V_{CC}$ +0.5V to $V_{CC}$ +0.3V Redefined I <sub>CC</sub> values for Com'l and Ind'l temperature ranges I <sub>CC</sub> (Com'l): Changed from 100, 80 and 70 mA to 90, 80 and 75 mA for 8, 10 and 12ns speed bins respectively I <sub>CC</sub> (Ind'l): Changed from 80 and 70 mA to 90 and 85 mA for 10 and 12ns speed bins respectively Modified Note# 4 on AC Test Loads Added Static Discharge Voltage and latch-up current spec Added $V_{IH(max)}$ spec in Note# 2 Changed reference voltage level for measurement of Hi-Z parameters from ±500 mV to ±200 mV Added Data Retention Characteristics Table and footnote on t <sub>R</sub> Added Write Cycle (WE Controlled, OE HIGH During Write) Timing Diagram Changed package name for 44-pin TSOP II from Z to ZS Added 8 ns parts in the Ordering Information table Shaded Ordering Information Table
*В	459073	See ECN	NXR	Converted Preliminary to Final. Removed $-8$ and $-12$ Speed bins Removed Commercial Operating Range from product offering. Changed the description of I <sub>IX</sub> from "Input Load Current" to "Input Leakage Current" Updated the Thermal Resistance table. Changed t <sub>HZBE</sub> from 5 ns to 6 ns. Updated footnote #7 on High-Z parameter measurement Added footnote #12. Updated the Ordering Information and replaced Package Name column with Package Diagram in the Ordering Information table.
*C	480177	See ECN	VKN	Added -10BVI product ordering code in the Ordering Information table.
*D	3059162	10/14/2010	PRAS	Added Ordering Code Definitions. Updated Package Diagrams.
*E	3098812	12/01/2010	PRAS	Added Acronyms and Units of Measure. Minor edits and updated in new template.
*F	3861347	01/08/2013	TAVA	Updated Ordering Information (Updated part numbers). Updated Package Diagrams: spec 51-85087 – Changed revision from *C to *E. spec 51-85150 – Changed revision from *F to *H.
*G	4187715	11/10/2013	MEMJ	Updated in new template.
				Completing Sunset Review.



## Document History (continued)

Document Title: CY7C1011DV33, 2-Mbit (128 K × 16) Static RAM Document Number: 38-05609					
Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change	
۴H	4567909	11/12/2014	MEMJ	Updated Functional Description: Added "For a complete list of related resources, click here." at the end. Updated Switching Waveforms: Added Note 23 and referred the same note in Figure 10. Competing Sunset Review.	



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